

# ESDLC5V0D8B

## Description

The ESDLC5V0D8B in a SOD-882 package and will protect bidirectional line. These devices are designed to replace multilayer varistors (MLVs) in portable applications such as cell phones, notebook computers, and PDA's. They offer superior electrical characteristics such as lower clamping voltage and no device degradation when compared to MLVs, The ESDLC5V0D8B are designed to protect sensitive semiconductor components from damage or upset due to electrostatic discharge (ESD),and other voltage induced transient events.

#### Feature

- Case : SOD882 package
- Low Capacitance 3 pF
- Low clamping voltage
- Low Leakage current
- Response Time is Typically < 1.0 ns
- IEC61000 4 2 Level 4 ESD Protection
- This is a Pb-Free Device

## Applications

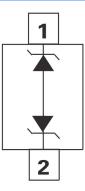
- Cellular phones
- Portable devices
- Digital cameras
- Power supplies

#### **Absolute Maximum Ratings**

Parameter	Symbol	Value	Units
IEC61000-4-2 (Contact)	V <sub>ESD</sub>	10	kV
IEC61000-4-2 (Air)	$V_{ESD}$	15	kV
Lead Soldering Temperature	TL	260 (10 sec)	°C
Operating Temperature	TJ	-55 to 125	°C
Storage Temperature Range	T <sub>STG</sub>	-55 to 150	°C



#### Schematic & PIN Configuration

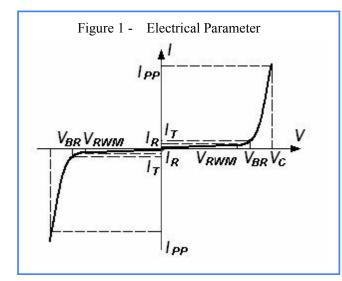




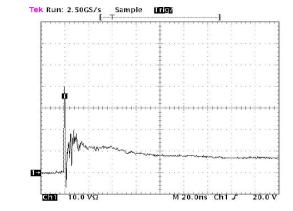
# Electrical Characteristics (T = 25° C)

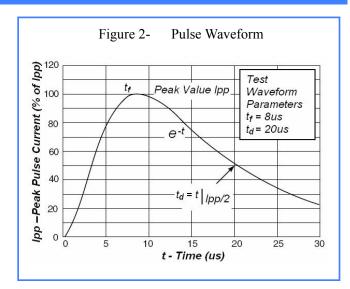
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Reverse Stand-off Voltage	V <sub>RWM</sub>				5	V
Reverse Breakdown Voltage	$V_{BR}$	lt = 1mA	5.5			V
Reverse Leakage Current	I <sub>R</sub>	V <sub>R</sub> =V <sub>RWM</sub>			100	nA
Clamping Voltage	Vc	I <sub>PP</sub> =3.5A, t <sub>P</sub> = 8/20μs		11.5		V
Peak pulse Current	I <sub>PP</sub>	t <sub>P</sub> = 8/20µs			3.5	А
Junction Capacitance	CJ	V <sub>R</sub> =0V, f = 1MHz		2.7	3.5	pF

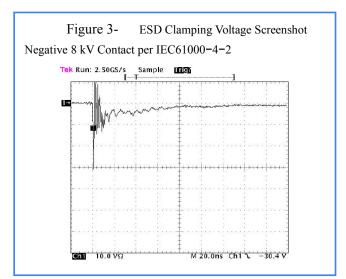
## Rating & Characteristic Curves





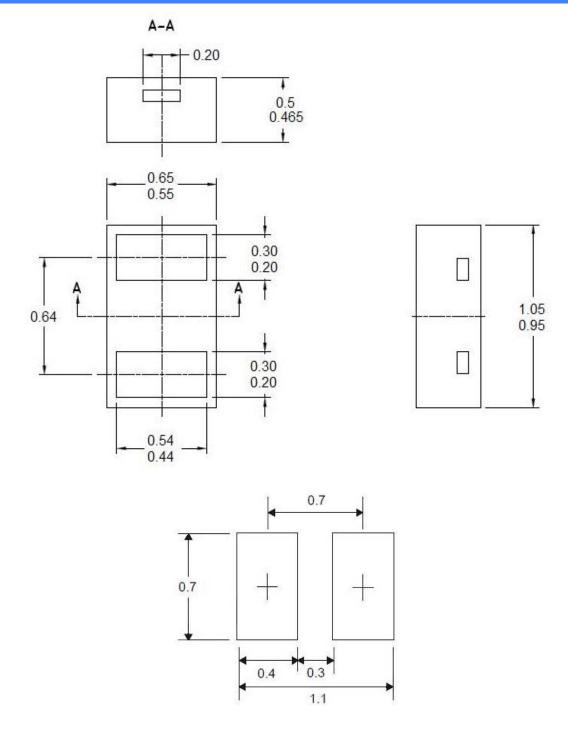








# PACKAGE OUTLINE DIMENSIONS in millimeters :SOD882



# Disclaimer

Specifications are subject to change without notice.

The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.

Users should verify actual device performance in their specific applications.